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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/606,823	06/26/2003	Shih-Ming Chang	67,200-1010	5507
TUNG & ASSO	7590 05/15/200° OCIATES		EXAM	INER
Suite 120			GARCIA, JOANNIE A	
838 W. Long L Bloomfield Hil		•	ART UNIT PAPER NUMBER 2823	
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			MAIL DATE	DELIVERY MODE
			05/15/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary		Application No.	Applicant(s)			
		10/606,823	CHANG ET AL.			
		Examiner	Art Unit			
		Joannie A. García	2823			
The MAILI Period for Reply	NG DATE of this communication app	ears on the cover sheet with the c	orrespondence address			
WHICHEVER IS  - Extensions of time ma after SIX (6) MONTHS  - If NO period for reply in Failure to reply within Any reply received by	STATUTORY PERIOD FOR REPLY LONGER, FROM THE MAILING DA by be available under the provisions of 37 CFR 1.13 6 from the mailing date of this communication. is specified above, the maximum statutory period we the set or extended period for reply will, by statute, the Office later than three months after the mailing ljustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).			
Status						
1) Responsive	e to communication(s) filed on 27 Fe	ebruary 2007.				
· <u>—</u>	This action is FINAL. 2b) This action is non-final.					
3) Since this a	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in a	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claim	ns					
4)⊠ Claim(s) <u>25</u>	5-30,32,33 and 39 is/are pending in	the application.				
4a) Of the a	4a) Of the above claim(s) is/are withdrawn from consideration.					
5) Claim(s)	5) Claim(s) is/are allowed.					
6)⊠ Claim(s) <u>25</u>	☑ Claim(s) <u>25-30,32,33 and 39</u> is/are rejected.					
7) Claim(s)	7) Claim(s) is/are objected to.					
8) Claim(s) are subject to restriction and/or election requirement.						
Application Papers						
9)☐ The specific	ation is objected to by the Examine	r.				
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
11)☐ The oath or	declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PTO-152.			
Priority under 35 U.	S.C. § 119					
12) Acknowledg	ment is made of a claim for foreign Some * c) None of:	priority under 35 U.S.C. § 119(a)	e-(d) or (f).			
1. Certified copies of the priority documents have been received.						
2. Certified copies of the priority documents have been received in Application No						
3. Copies of the certified copies of the priority documents have been received in this National Stage						
application from the International Bureau (PCT Rule 17.2(a)).						
* See the attached detailed Office action for a list of the certified copies not received.						
Attachment(s)						
<ol> <li>Notice of Reference</li> <li>Notice of Draftspers</li> </ol>	s Cited (PTO-892) on's Patent Drawing Review (PTO-948)	4) Interview Summary Paper No(s)/Mail Da				
	re Statement(s) (PTO/SB/08)	5) Notice of Informal P 6) Other:				

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The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 25-30, 32, 33, and 39, are rejected under 35 U.S.C. 102(b) as being anticipated by Higashikawa et al (U.S. Patent 6,319,637).

Higashikawa et al discloses a lithographic semiconductor fabrication process comprising exposing a semiconductor wafer to a first mask part that comprises a layout for a semiconductor device that is at least defective to form a defectively exposed portion (Figure 2A, and Column 7, lines 7-10), exposing the defectively exposed portion to a second mask part corresponding to the first mask part substantially free from defects or with defects at different locations that comprises another layout for the semiconductor device that is at least substantially free from defects or with defects at different locations, a second and a third time, to at least partially repair said defectively exposed portion (Figures 2A-2E, and Column 7, lines 35-67), wherein the first and second mask parts are formed on a same photomask (Figure 2A), and wherein said first mask part and said second mask part are on different photomasks (Figures 2C-2D, and 3A-3B, Column 5, lines 7-8, and Column 7, lines 35-67), exposing the defectively exposed portion to a third mask part one or more times (Figures 2A-2E), exposing the defectively exposed portion to the second mask part a second and a third time, or one or more times (Column 7, lines 45-67), and exposing the defectively exposed portion to the second, a third and other additional mask parts one or more additional times (Figures 2A-2E, and Column 7, lines 21-67).

Applicant argues that Higashikawa et al does not teach a first mask part at least partially defective, and exposing the defectively exposed portion substantially free for defects or with defect at different locations. However, Higashikawa et al discloses a first mask part at least partially defective, and exposing the defectively exposed portion substantially free for defects or with defect at different locations, as show in Figures 2A-2E, and 3A-3B, and as disclosed in Column 7, lines 5-50.

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Joannie García whose telephone number is (571) 272-1861. The examiner can normally be reached on Monday through Friday.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith, can be reached on (571) 272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

George Nourson
Primary Examiner
Art Unit 2823

JAG

May 9, 2007

GFourson

**Primary Examiner**